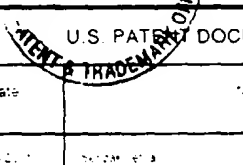


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b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION	MESSAGE
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1657		SERIAL NO. 09 905,320	
LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT: Cam Basceri et al.			
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U.S. PATENT DOCUMENTS

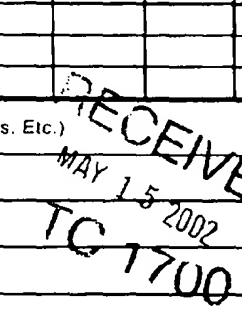
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FOREIGN PATENT DOCUMENTS

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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

Author	Title	Date	Pertinent Pages	Etc.



EXAMINER <i>E. Tuller</i>	DATE CONSIDERED 7/4/02
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\*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22 2687	SERIAL NO. 69608426
LIST OF ART CITED BY APPLICANT <small>(For official records of examination)</small>		APPLICANT Gen. Bascetta et al.	
		FILING DATE Feb. 15, 2007	GROUP I

**U.S. PATENT DOCUMENTS**

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**FOREIGN PATENT DOCUMENTS**

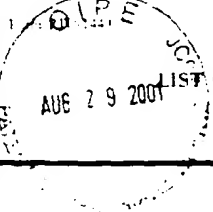
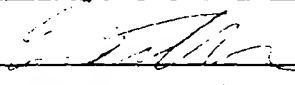
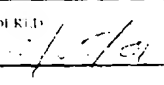
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**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)**

<div style="font-size: 2em; font-weight: bold; text-align: center;">CF</div>	AR   AS   AT	<div style="margin-bottom: 5px;">             Kim, et al. <i>Structural and Electrical Properties of BaTiO<sub>3</sub> grown on p-InP (100) by low-pressure metalorganic chemical vapor deposition at low temperature</i>. <i>Applied Physics Letters</i>, U.S. American Institute of Physics Vol. 65, No. 15, 10-1094, Pgs. 1955-1957           </div>

EXAMINER 	DATE CONSIDERED 12/05/06
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with text communication to applicant.

		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APP. DOCKET NO. M22 1677		SERIAL NO. 00065320	
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		APPLICANT Sanyo Electric Co., Ltd.		FILING DATE Jan. 23, 2002		GROUP I, Class 360	
U.S. PATENT DOCUMENTS							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
EF	AK	S. Yamamuchi et al., Abstract, <i>Ba-Sr-TiO<sub>2</sub> ratio dependence of the dielectric properties for (Ba<sub>1-x</sub>Sr<sub>x</sub>)TiO<sub>3</sub> thin films prepared by ion beam sputtering</i> , 63 APPLIED PHYSICS LETTERS No. 13, pp. 1644-1646 (1994).					
EF	AS	M. Yamamuka et al., Abstract, <i>Thermal-Desorption Spectroscopy of (Ba<sub>1-x</sub>Sr<sub>x</sub>)TiO<sub>3</sub> Thin Films Prepared by Chemical Vapor Deposition</i> , 35 JPN. J. OF APPL. PHYS. Pt. 1, No. 2A, pp. 729-735 (1996).					
EF	AT	Arai T. et al., <i>Preparation of SrTiO<sub>3</sub> Films on Si/SiO<sub>2</sub> Wafers by Chemical Vapor Deposition</i> , Jap. Journal of Applied Physics, Vol. 35, No. 9B, Part 02, pp. 4875-4876.					
EXAMINER				DATE CONSIDERED			
							
<small>*EXAMINER: Initial reference considered, whether or not citation is in accordance with MPEP 609. Draw line through citation if not in accordance and not considered. Include a page reference with text in margin of applicant.</small>							

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M1221967		SERIAL NO. 00963326		
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LIST OF ART CITED BY APPLICANT <small>(use several sheets if necessary)</small>		FILING DATE Jul 15, 2001		GROUP Unknown		
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	AN					
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
EF	AR		Takaaki Kawahara et al., (Ru, SrTiO <sub>3</sub> ) Films Prepared by Liquid Source Chemical Vapor Deposition on Ru Electrodes, 35 Jpn. J.			
			AIP, PHYS. PL. 1, No. 9B, pp. 4880, 4883 (1996)			
LF	AS		Rajesh Khumbar et al., A Novel Low-Temperature Process for High Dielectric Constant BST Thin Films for 1T1M DRAM			
			Applications, Microelectronics Research Center, Univ. of Texas at Austin, TX (Undated), 2 pages			
CF	AT		Yong Tae Kim et al., Abstract, Advantages of Ru <sup>2+</sup> bottom electrode in the dielectric and leakage characteristics of			
			(Ru SrTiO <sub>3</sub> ) capacitor, 35 Jpn. J. AIP, PHYS. PL. 1, No. 12A, pp. 6153-6156 (1996)			
EXAMINER			DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>						

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPL. DOCKET NO. M122 1657	SERIAL NO. 00908 320
<b>LIST OF ART CITED BY APPLICANT</b> <small>Use separate sheets if necessary</small>		APPLICANT Gen. Electric Co.	
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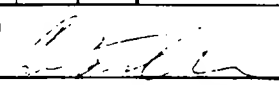
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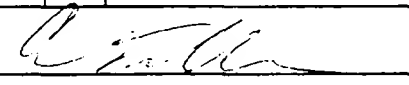
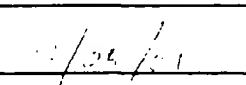
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OTHER REFERENCES - including Author, Title, Date, Pertinent Pages, Etc.			
EF	AR		S.H. Park et al., Abstract, <i>Characterization of MIS capacitor of BST thin films deposited on Si by RF magnetron sputtering</i> Ferroelectric Thin Films V, Scarsdale, San Francisco, CA, pp. 33-38 (April 7, 1995)
EF	AS		N. Takeuchi et al., Abstract, <i>Effect of firing atmosphere on the cubic hexagonal transition in Bi<sub>1-x</sub>Sm<sub>x</sub>TiO<sub>3</sub> 98 NISSAN</i> SHIMADZU KYOKAI GAKKAI SHI RONBUNSHU No. 5, pp. 539-549 (1990)
EF	AI		H. Yamaguchi et al., Abstract, <i>Reactive coevaporation synthesis and characterization of SrTiO<sub>3</sub>/BaTiO<sub>3</sub> thin films, IEEE</i> International Symposium on Applications of Ferroelectrics, Greenville, SC pp. 285-288 (August 2, 1992)

EXAMINER 	DATE CONSIDERED 12/15/01
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\*EXAMINER - Initial if reference considered whether or not citation is in conformance with MPEP 609. Draw free through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M1221657	SERIAL NO. UNKNOWN	4071 U.S. PTO 09/905320 07/13/01		
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EE	AB	09 476 515		Cem Bascer as filed and as amended			01 03 00	
EE	AC	09 580 733		Cem Bascer as filed			05 25 00	
EE	AD	5 459 625	10 17 55	Tomczawa et al	361	321.5		
EE	AE	5 618 751	04 08 97	Eguchi et al	438	785		
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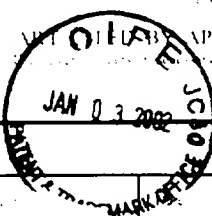
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				FILING DATE JUN 13, 2000		CLASS H01L 26/00	
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E	AA	5,286,485	10/26/93	Nakazawa			
E	AB	5,751,948	01/21/97	Endo			
E	AC	5,776,254	03/24/98	Yabuzo et al.			
E	AD	5,783,254	07/07/98	Yusui et al.			
E	AE	5,798,935	07/21/98	Roh			
E	AF	6,043,526	08/25/98	Dhoke et al.			
E	AG	6,046,346	03/28/00	Ochiai			
E	AH	6,078,492	04/04/00	Kadokura et al.			
E	AI	6,153,895	06/20/00	Hama et al.			
E	AJ	6,037,209	11/28/00	Watanabe			
E	AK	6,037,205	03/14/00	Huh et al.			
FOREIGN PATENT DOCUMENTS							
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E	AL	0,855,755 A2	26/01/98	EPO - Zhao et al., Applied Materials, Inc.			
E	AM	0,957,522 A2	12/05/99	EPO - Ueda, Matsubara, Matsubara Electric Ind. Co.			
E	AN	WO 98/04097	20/02/98	WIPO - Simpson, John et al.			
E	AO	0,474,140 A1	30/08/91	EPO - Kamayama, Sanoh et al., NEC Corporation			
E	AP	WO 99/44645	11/06/99	WIPO - Narwankar et al., Applied Materials, Inc.			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
E	AR			Steve Bilodeau et al., <i>Composition Dependence of the Dielectric Properties of MOCVD Ba-Sr LTO</i> , pp. 1-21, MRS Fall Meeting, 12/01/96			
E	AS			Steve M. Bilodeau et al., <i>MOCVD EML for High Density DRAM Applications</i> (Preprint for SEMICONWEST 07/12/95), 2 pages			
E	AT			Y. C. Zeng et al., <i>Abstract, Improvements in the Properties of Chemical Vapor-Deposited (Ba,Sr)F<sub>2</sub> Films Through Use of a Seed Layer</i> , 6 JIN J. APPL. PHYS. Pt. 1, No. 11, pp. 6824-6828 (1997)			
EXAMINER				DATE CONSIDERED			
							
<small>*EXAMINER: Initial reference considered, whether or not citation is in compliance with MPEP 609. Dashed line through citation indicates not in compliance and not considered. For complete of this form with text continuing on to another page.</small>							





Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1657		SERIAL NO. 09/905,320	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Cem Basceri et al.			
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EF	AC	09/346,080		Agarwal et al. (As filed, and amended in response to 06/29/01 Office Action; 12/20/00 Office Action, and 11/29/01 Office Action)			August 20, 1999
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EXAMINER <i>E. P. Smith</i>				DATE CONSIDERED 9/30/02			
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLICATION FOR PATENT		CLASSIFICATION NUMBER	
LIST OF ARTS AND APPLICANTS				FIELD OF INVENTION	
TITLE OF INVENTION				INVENTOR'S NAME	



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